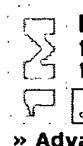


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Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

```
(signal <phrase> (detection
<or> detecting)) <and> (dial
<phrase> (indicator <or>
display <or> meter)) <and>
```

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

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(signal <phrase> (detection <or> detecting)) <and> (

☐ Check to search within this result set

Results Key:

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Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

```
(internal <phrase> computer  
<phrase> (state <or> status  
<or> condition))
```

Start Search**Clear**

Note: This function returns plural and suffixed forms of the keyword(s).

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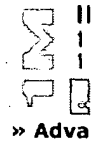
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Results:
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3) Limit the results by selecting Search Options.

4) Click Search. See [Search Examples](#)

```
(internal <phrase> computer  
<phrase> (state <or> status  
<or> condition) <phrase>  
(meter <or> indicator))
```

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dial <phrase> meter

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Results Key:

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1 **Physically-based geometric constraint resolution**
Inui, M.; Tohyama, H.; Miura, M.;

Assembly and Task Planning, 2001, Proceedings of the IEEE International Symposium on , 28-29 May 2001

Pages:393 - 398

[\[Abstract\]](#)
[\[PDF Full-Text \(480 KB\)\]](#)
IEEE CNF

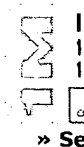
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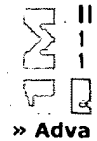
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 computer <phrase> internal
<phrase> environment

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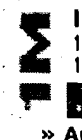
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» Enter a name to find an author:



Example: Enter Lockett S to obtain a list of authors with the last name Lockett and first name initial S.
OR» Select a letter to browse the author list:

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Davis A. J.	Davis A. K.	Davis A. L.	Davis A. M.	Davis A
Davis A. O.	Davis A. P.	Davis A. R.	Davis A. S.	Davis A
Davis A. W.	Davis B.	Davis B. A.	Davis B. C.	Davis E
Davis B. J.	Davis B. K.	Davis B. R.	Davis B. S.	Davis E
Davis B. V.	Davis B. W.	Davis C.	Davis C. A.	Davis C
Davis C. B.	Davis C. C.	Davis C. D.	Davis C. E.	Davis C
Davis C. G.	Davis C. H.	Davis C. J.	Davis C. Jr.	Davis C
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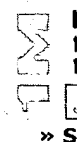
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1 Demonstration of a fiber optic array of three-axis magnetometers for undersea application
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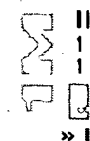
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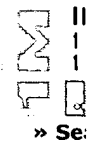
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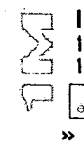
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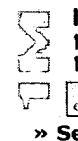
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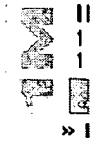
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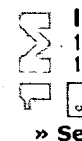
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